

## 20-40GHz High Gain Buffer Amplifier GaAs Monolithic Microwave IC

### Description

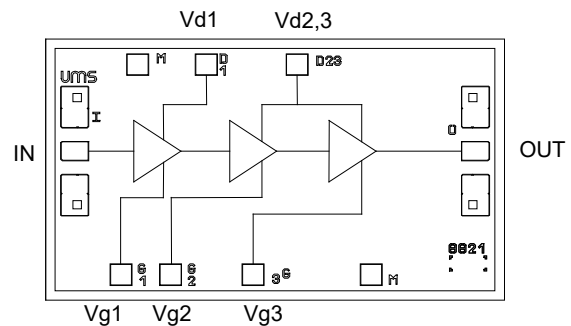
The CHA2098b99F is a high-gain, broadband three-stage monolithic buffer amplifier designed for applications ranging from military to commercial communication systems. The backside of the chip serves as both RF and DC ground, simplifying the assembly process.

The circuit is manufactured with a pHEMT process, via holes through the substrate, air bridges and electron-beam gate lithography.

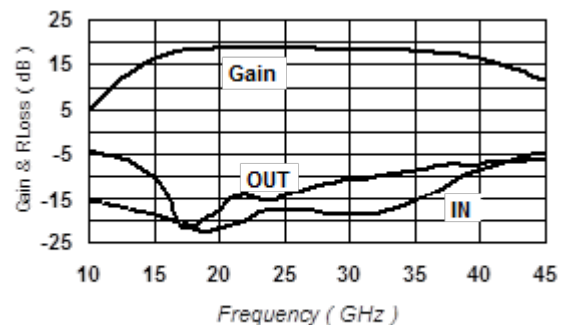
The device is available in chip form.

### Main Features

- Broadband performances: 20 - 40GHz
- 16 dBm output power (1dB gain comp)
- 19 dB gain with 1.5 dB flatness
- Low DC power consumption, 150mA@3.5V
- Chip size: 1.67 X 0.97 X 0.10mm



*Typical on wafer measurement*  
Gain & Input and Output Loss vs. Frequency



### Main Characteristics

$T_{\text{backside}} = 25^{\circ}\text{C}$

Symbol	Parameter	Min	Typ	Max	Unit
Fop	Operating frequency range	20		40	GHz
G	Small signal gain	17	19		dB
P1dB	Output power at 1dB gain compression	13	16		dBm
Id	Bias current		150	200	mA

## Electrical Characteristics for Broadband Operation

$T_{\text{backside}} = +25^{\circ}\text{C}$ ,  $V_{d1,2,3} = 3.5\text{V}$

Symbol	Parameter	Min	Typ	Max	Unit
Fop	Operating frequency range (1)	20		40	GHz
G	Small signal gain (1)	17	19		dB
$\Delta G$	Small signal gain flatness (1)		$\pm 1.5$		dB
Is	Reverse isolation (1)		30		dB
P1dB	Output power at 1dB gain compression (1)	13	16		dBm
P3dB	Output power at 3dB gain compression	15	16		dBm
VS.WRin	Input VS.WR (1)			3.0:1	
VS.WRout	Output VS.WR (1)			3.0:1	
NF	Noise Figure			10.0	dB
Id	Bias current		150	200	mA

(1) These values are representative of on-wafer measurements that are made without bonding wires at the RF ports.

## Absolute Maximum Ratings

$T_{\text{backside}} = 25^{\circ}\text{C}$  (1)

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	4.5	V
Id	Drain bias current	200	mA
Vg	Gate bias voltage	-2.0 to +0.4	V
Ta	Operating temperature range	-40 to +85	$^{\circ}\text{C}$
Tstg	Storage temperature range	-55 to +150	$^{\circ}\text{C}$

(1) Operation of this device above any one of these parameters may cause permanent damage.

## Device thermal performances

All the figures given in this section are obtained assuming that the die is only cooled down by conduction through the chip backside.

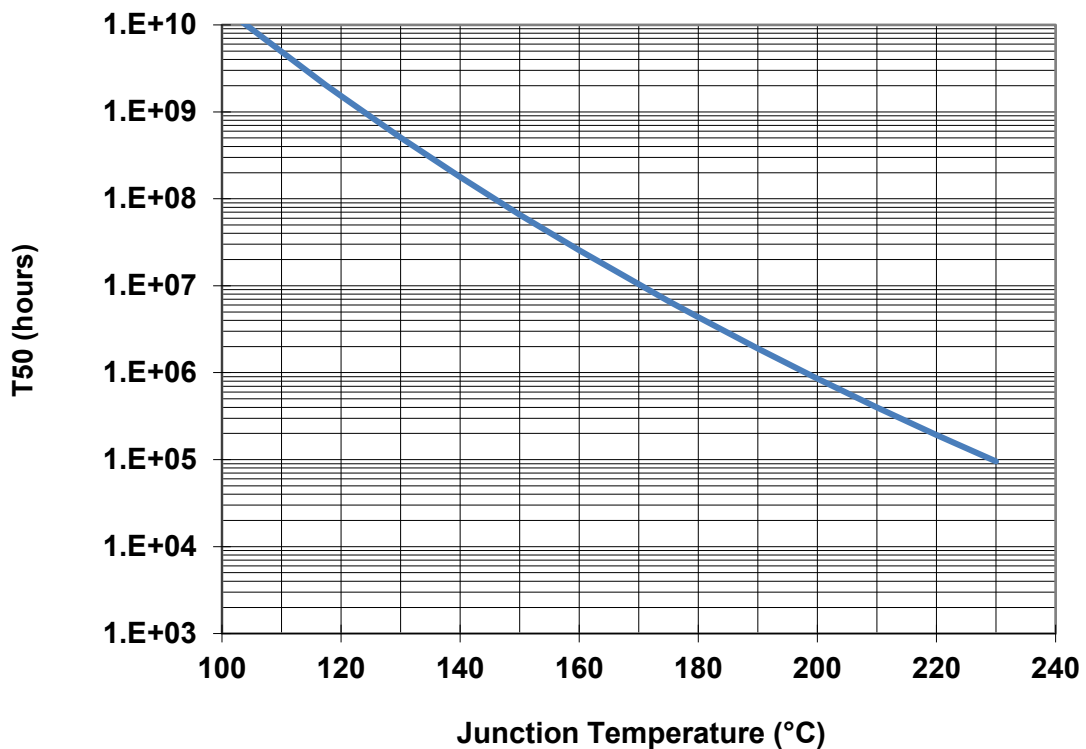
The temperature is monitored at the package back-side interface ( $T_{\text{case}}$ ).

The system maximum temperature must be adjusted in order to guarantee that  $T_{\text{junction}}$  remains below the maximum value specified in the Absolute Maximum Ratings table.

So, the system PCB must be designed to comply with this requirement.

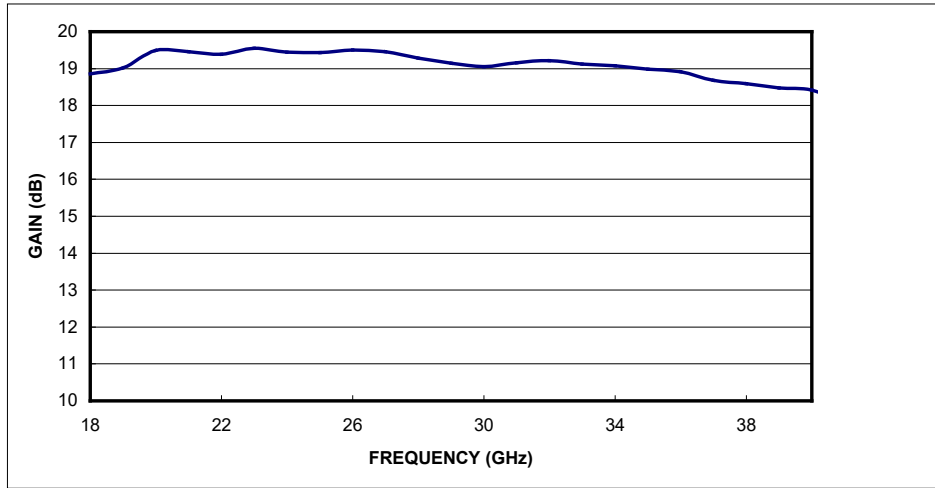
Parameter	Biasing conditions	$T_{\text{junction}}$ (°C)	$R_{\text{TH}}$ (°C/W)	$T_{50}$ (hours)
$R_{\text{TH}}^{(1)}$ Thermal Resistance (Junction to Case)	Vd= 3.5 V Id= 170 mA Pdiss= 0.596 W	155	117.4	4.08E+07

(1) Assuming 85°C  $T_{\text{backside}}$

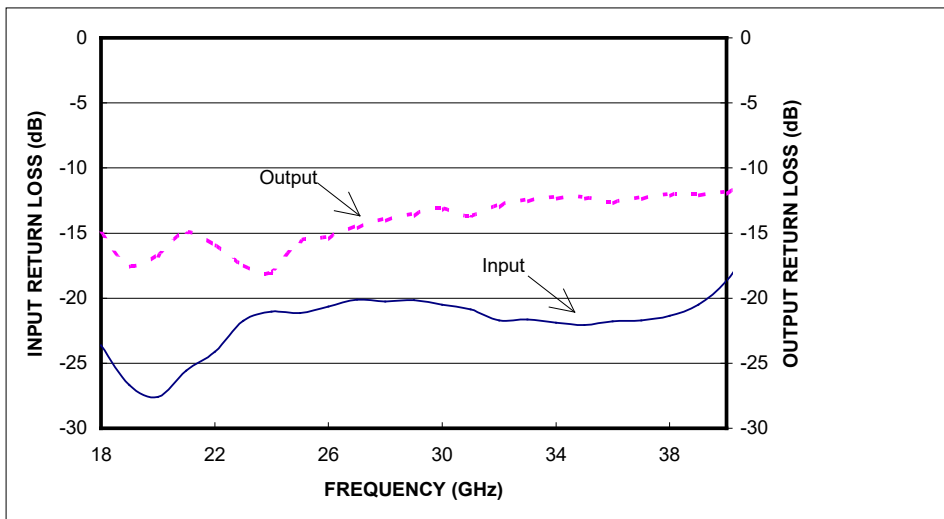


## Typical Performance

$T_{\text{backside}} = +25^{\circ}\text{C}$ ,  $V_d = 3.5\text{V}$ ,  $V_g = -0.1\text{V}$



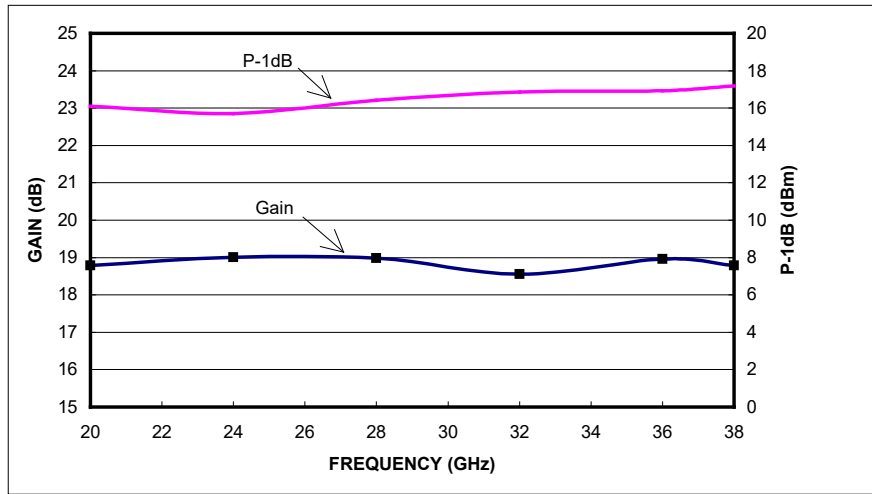
Gain vs. Frequency



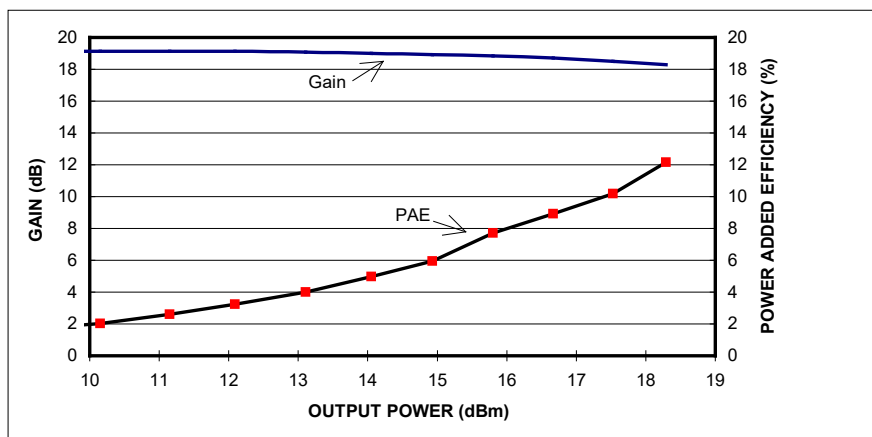
Input and Output Loss vs. Frequency

**Typical Performance**

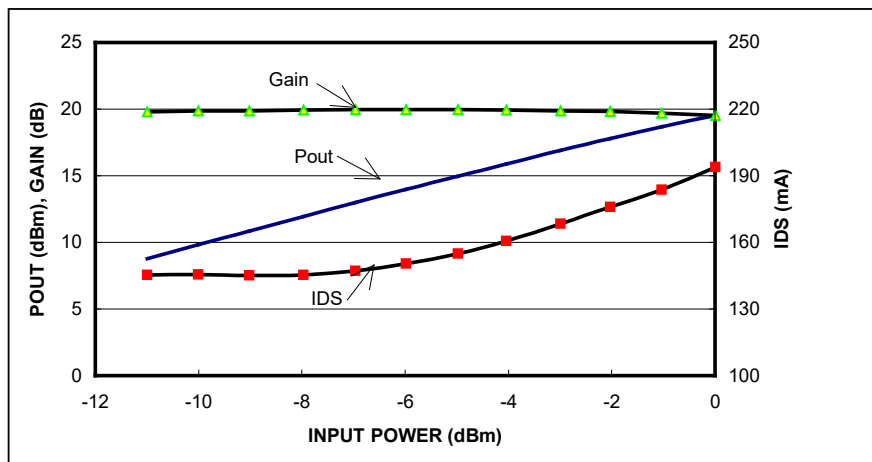
$T_{\text{backside}} = +25^{\circ}\text{C}$ ,  $V_d = 3.5\text{V}$ ,  $V_g = -0.1\text{V}$



**Gain and Compressed Power vs. Frequency**



**Gain and Efficiency vs. Output Power (F=30GHz)**



**Gain, Output Power and IDS vs. Input Power (F=38GHz)**

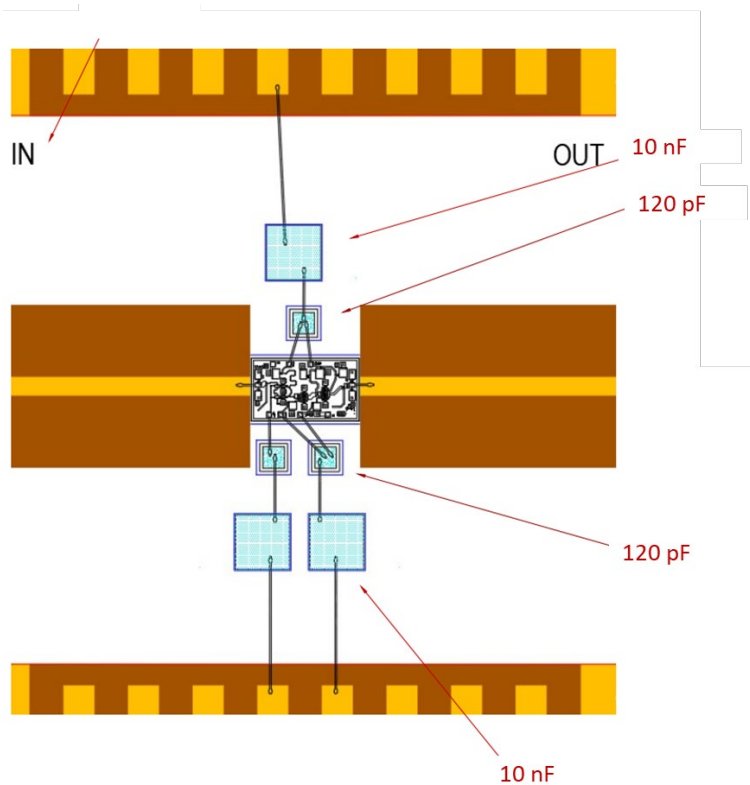
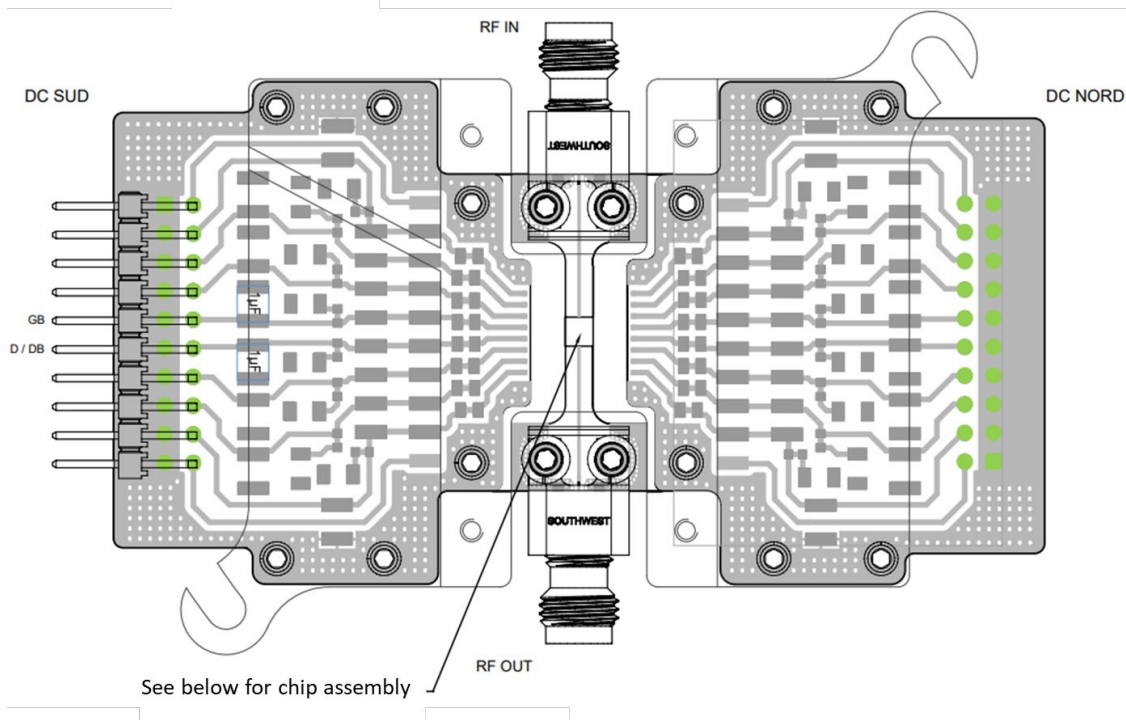


## Typical Sij parameters (on Wafer)

Bias conditions:  $V_d = 3.5V$ ,  $V_g = 0V$

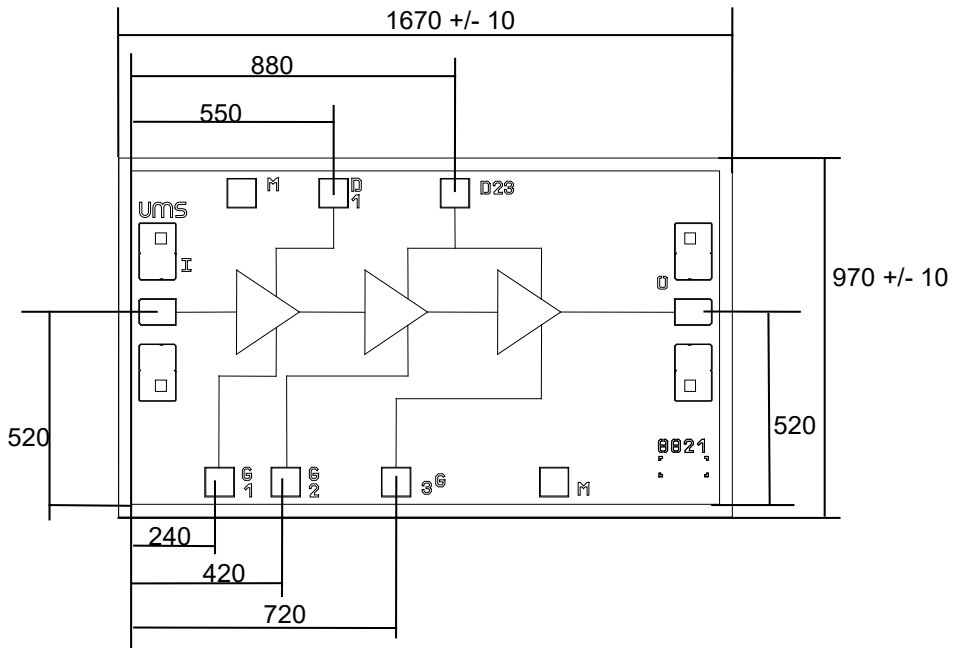
Freq. GHz	S11 dB	S11 /°	S12 dB	S12 /°	S21 dB	S21 /°	S22 dB	S22 /°
15	-18.37	116.1	-69.59	148.0	16.72	130.6	-7.99	77.7
16	-19.49	113.8	-65.95	154.4	18.13	102.0	-10.02	51.4
17	-20.63	113.4	-65.20	-158.1	18.90	73.7	-13.84	20.3
18	-22.15	114.4	-60.58	155.1	19.31	46.4	-16.29	-13.8
19	-24.36	120.5	-58.79	155.7	19.42	22.3	-19.17	-64.4
20	-26.49	140.0	-54.42	136.8	19.97	-1.6	-18.06	-99.8
21	-24.05	163.8	-51.83	127.3	19.63	-27.5	-16.16	-138.5
22	-22.26	156.6	-52.04	81.3	18.79	-46.8	-16.79	-168.8
23	-21.20	159.0	-60.55	107.0	18.65	-57.2	-17.79	168.2
24	-20.46	150.9	-54.03	100.6	19.86	-80.0	-18.36	-171.8
25	-20.57	148.8	-50.49	90.6	19.82	-102.7	-15.84	175.6
26	-20.37	145.4	-49.95	75.8	19.89	-121.3	-15.59	171.0
27	-20.01	141.8	-49.48	67.0	19.82	-142.0	-14.72	159.9
28	-20.38	136.9	-48.65	53.7	19.60	-161.3	-14.17	154.0
29	-20.51	132.4	-48.33	37.5	19.53	-179.4	-13.37	144.0
30	-21.26	127.2	-49.24	25.1	19.45	162.3	-12.84	131.6
31	-21.82	125.6	-47.95	22.8	19.64	144.2	-13.15	123.6
32	-22.62	129.0	-47.60	3.6	19.53	123.6	-12.50	114.6
33	-21.97	127.4	-48.30	-3.7	19.28	104.7	-12.28	102.1
34	-22.69	118.7	-45.57	-22.6	19.27	86.4	-11.93	93.5
35	-23.12	114.3	-47.53	-45.6	19.15	66.9	-11.82	79.2
36	-22.50	103.9	-48.92	-49.1	18.96	46.8	-12.13	67.7
37	-22.15	91.0	-48.07	-69.1	18.52	28.3	-12.07	58.5
38	-20.65	71.9	-49.33	-67.4	18.36	10.1	-11.87	47.6
39	-18.94	39.2	-46.75	-105.6	18.43	-9.4	-10.98	36.1
40	-17.28	8.4	-47.08	-108.5	18.34	-31.1	-10.60	19.8
41	-14.60	-18.5	-48.00	-134.6	17.82	-53.7	-10.11	6.4
42	-12.20	-40.3	-47.52	-160.4	17.39	-76.8	-9.83	-7.0
43	-10.21	-59.7	-46.21	160.6	16.75	-99.2	-9.28	-20.8
44	-8.25	-80.9	-49.74	147.7	15.88	-123.1	-8.54	-37.0
45	-6.83	-97.6	-48.99	136.5	14.64	-145.6	-8.12	-50.7
46	-5.68	-113.3	-53.12	32.5	13.15	-167.2	-7.61	-62.9
47	-4.73	-129.1	-50.08	-34.8	11.65	172.2	-7.25	-77.1

**Evaluation board**



The decoupling network used is composed of 2 levels of parallel capacitors. The first level is 120pF chip capacitor. The second level is 10nF chip capacitor. The two levels should be as close as possible to the die.

## Mechanical Data

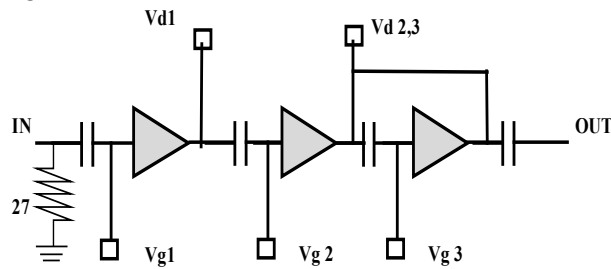


### Bonding pad positions.

(Chip thickness : 100µm. All dimensions are in micrometers)

## Typical Bias Tuning

The circuit schematic is given below:



For typical operation, the three drain biases are connected altogether. In a same way, all the gate biases are connected together at the same power supply, tuned to drive a small signal operating current of 130mA. A separate access to the gate voltages of each stage (Vg1,2 & 3) is provided for the fine tuning of the stages regarding the application.

## Recommended environmental management

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <https://www.ums-rf.com>.

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## Recommended ESD management

Refer to the application note AN0020 available at <https://www.ums-rf.com> for ESD sensitivity and handling recommendations for the UMS products.

## Recommended Evaluation board EVB assembly

Refer to the application note AN0030 available at <https://www.ums-rf.com> Evaluation board EVB.

## Ordering Information

Die form	CHA2098b99F/00
Evaluation board	EVB-CHA2098b99F

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